

CYPRESS

CY54/74FCT374T**CY54/74FCT574T**

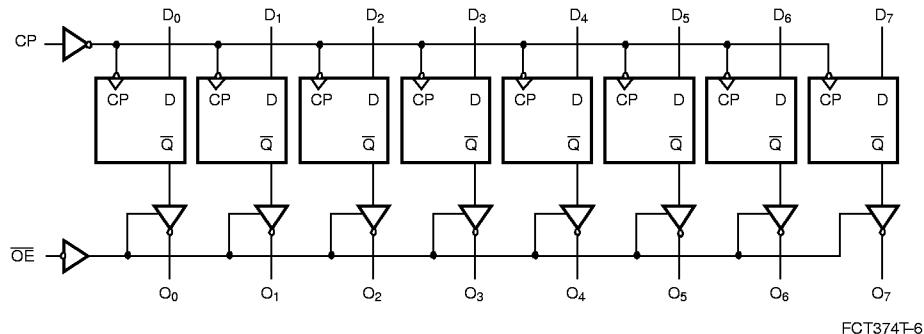
8-Bit Registers

Features

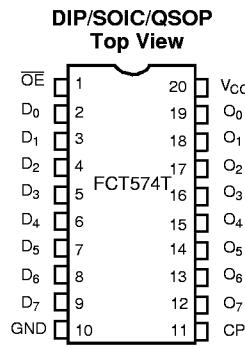
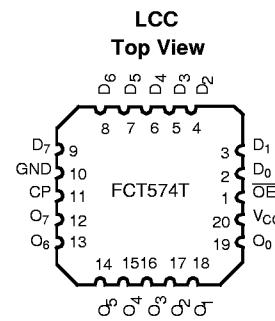
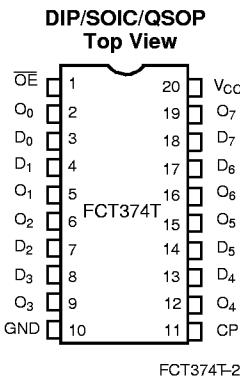
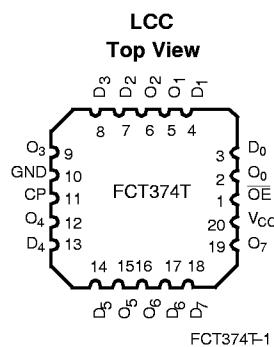
- Function, pinout, and drive compatible with FCT and F logic
- FCT-C speed at 5.2 ns max. (Com'l)
FCT-A speed at 6.5 ns max. (Com'l)
- Reduced V_{OH} (typically = 3.3V) versions of equivalent FCT functions
- Edge-rate control circuitry for significantly improved noise characteristics
- Power-off disable feature

- Matched rise and fall times
- Fully compatible with TTL input and output logic levels
- ESD > 2000V
- Extended commercial range of -40°C to +85°C
- Sink Current 64 mA (Com'l), 32 mA (Mil)
Source Current 32 mA (Com'l), 12 mA (Mil)
- Edge-triggered D-type inputs
- 250 MHz typical toggle rate

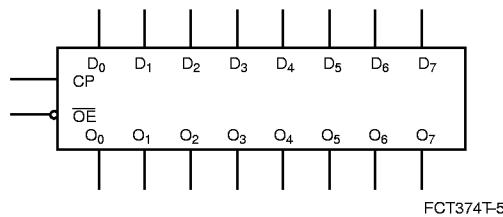
Logic Block Diagram



Pin Configurations



Logic Symbol



Functional Description

The FCT374T and FCT574T are high-speed low-power octal D-type flip-flops featuring separate D-type inputs for each flip-flop. Both devices have three-state outputs for bus oriented applications. A buffered clock (CP) and output enable (\overline{OE}) are common to all flip-flops. The FCT574T is identical to FCT374T except for flow-through pinout to simplify board design. The eight flip-flops contained in the FCT374T and FCT574T will store the state of their individual D inputs that meet the set-up and hold time requirements on the LOW-to-HIGH clock (CP) transition. When \overline{OE} is LOW, the contents of the eight flip-flops are available at the outputs. When \overline{OE} is HIGH, the outputs will be in the high-impedance state. The state of output enable does not affect the state of the flip-flops.

The outputs are designed with a power-off disable feature to allow for live insertion of boards.

Function Table^[1]

Inputs			Outputs
D	CP	OE	O
H	—	L	H
L	—	L	L
X	X	H	Z

Electrical Characteristics Over the Operating Range

Parameter	Description	Test Conditions	Min.	Typ. ^[5]	Max.	Unit	
V_{OH}	Output HIGH Voltage	$V_{CC}=\text{Min.}, I_{OH}=-32\text{ mA}$	Com'l	2.0		V	
		$V_{CC}=\text{Min.}, I_{OH}=-15\text{ mA}$	Com'l	2.4	3.3	V	
		$V_{CC}=\text{Min.}, I_{OH}=-12\text{ mA}$	Mil	2.4	3.3	V	
V_{OL}	Output LOW Voltage	$V_{CC}=\text{Min.}, I_{OL}=64\text{ mA}$	Com'l		0.3	0.55	V
		$V_{CC}=\text{Min.}, I_{OL}=32\text{ mA}$	Mil		0.3	0.55	V
V_{IH}	Input HIGH Voltage		2.0			V	
V_{IL}	Input LOW Voltage				0.8	V	
V_H	Hysteresis ^[6]	All inputs		0.2		V	
V_{IK}	Input Clamp Diode Voltage	$V_{CC}=\text{Min.}, I_{IN}=-18\text{ mA}$		-0.7	-1.2	V	
I_I	Input HIGH Current	$V_{CC}=\text{Max.}, V_{IN}=V_{CC}$			5	μA	
I_{IH}	Input HIGH Current	$V_{CC}=\text{Max.}, V_{IN}=2.7\text{V}$			± 1	μA	
I_{IL}	Input LOW Current	$V_{CC}=\text{Max.}, V_{IN}=0.5\text{V}$			± 1	μA	
I_{OZH}	Off State HIGH-Level Output Current	$V_{CC} = \text{Max.}, V_{OUT} = 2.7\text{V}$			10	μA	
I_{OZL}	Off State LOW-Level Output Current	$V_{CC} = \text{Max.}, V_{OUT} = 0.5\text{V}$			-10	μA	
I_{OS}	Output Short Circuit Current ^[7]	$V_{CC}=\text{Max.}, V_{OUT}=0.0\text{V}$	-60	-120	-225	mA	
I_{OFF}	Power-Off Disable	$V_{CC}=0\text{V}, V_{OUT}=4.5\text{V}$			± 1	μA	

Notes:

1. H = HIGH Voltage Level. L = LOW Voltage Level X = Don't Care Z = HIGH Impedance = LOW-to-HIGH clock transition
2. Unless otherwise noted, these limits are over the operating free-air temperature range.
3. Unused inputs must always be connected to an appropriate logic voltage level, preferably either V_{CC} or ground.
4. T_A is the "instant on" case temperature.
5. Typical values are at $V_{CC}=5.0\text{V}$, $T_A=+25^\circ\text{C}$ ambient.
6. This parameter is guaranteed but not tested.
7. Not more than one output should be shorted at a time. Duration of short should not exceed one second. The use of high-speed test apparatus and/or sample and hold techniques are preferable in order to minimize internal chip heating and more accurately reflect operational values. Otherwise prolonged shorting of a high output may raise the chip temperature well above normal and thereby cause invalid readings in other parameters tests. In any sequence of parameter tests, I_{OS} tests should be performed last.

Capacitance^[2]

Parameter	Description	Typ. ^[5]	Max.	Unit
C_{IN}	Input Capacitance	5	10	pF
C_{OUT}	Output Capacitance	9	12	pF

Power Supply Characteristics

Parameter	Description	Test Conditions	Typ. ^[5]	Max.	Unit
I_{CC}	Quiescent Power Supply Current	$V_{CC}=\text{Max.}, V_{IN}\leq 0.2V, V_{IN}\geq V_{CC}-0.2V$	0.1	0.2	mA
ΔI_{CC}	Quiescent Power Supply Current (TTL inputs HIGH)	$V_{CC}=\text{Max.}, V_{IN}=3.4V$ ^[8] $f_1=0$, Outputs Open	0.5	2.0	mA
I_{CCD}	Dynamic Power Supply Current ^[9]	$V_{CC}=\text{Max.}, \text{One Bit Toggling},$ 50% Duty Cycle, Outputs Open, $\overline{OE}=\text{GND}, V_{IN}\leq 0.2V \text{ or } V_{IN}\geq V_{CC}-0.2V$	0.06	0.12	mA/MHz
I_C	Total Power Supply Current ^[10]	$V_{CC}=\text{Max.}, f_0=10 \text{ MHz},$ 50% Duty Cycle, Outputs Open, One Bit Toggling at $f_1=5 \text{ MHz}$, $\overline{OE}=\text{GND}, V_{IN}\leq 0.2V \text{ or } V_{IN}\geq V_{CC}-0.2V$	0.7	1.4	mA
		$V_{CC}=\text{Max.}, f_0=10 \text{ MHz},$ 50% Duty Cycle, Outputs Open, One Bit Toggling at $f_1=5 \text{ MHz}$, $\overline{OE}=\text{GND}, V_{IN}=3.4V \text{ or } V_{IN}=\text{GND}$	1.2	3.4	mA
		$V_{CC}=\text{Max.}, f_0=10 \text{ MHz},$ 50% Duty Cycle, Outputs Open, Eight Bits Toggling at $f_1=2.5 \text{ MHz}$, $\overline{OE}=\text{GND}, V_{IN}\leq 0.2V \text{ or } V_{IN}\geq V_{CC}-0.2V$	1.6	3.2 ^[11]	mA
		$V_{CC}=\text{Max.}, f_0=10 \text{ MHz},$ 50% Duty Cycle, Outputs Open, Eight Bits Toggling at $f_1=2.5 \text{ MHz}$, $\overline{OE}=\text{GND}, V_{IN}=3.4V \text{ or } V_{IN}=\text{GND}$	3.9	12.2 ^[11]	mA

Notes:

8. Per TTL driven input ($V_{IN}=3.4V$); all other inputs at V_{CC} or GND.
9. This parameter is not directly testable, but is derived for use in Total Power Supply calculations.
10. $I_C = I_{QUIESCENT} + I_{INPUTS} + I_{DYNAMIC}$
 $I_C = I_{CC} + \Delta I_{CC} D_H N_T + I_{CCD}(f_0/2 + f_1 N_1)$
 $I_{CC} = \text{Quiescent Current with CMOS input levels}$
 $\Delta I_{CC} = \text{Power Supply Current for a TTL HIGH input } (V_{IN}=3.4V)$
 $D_H = \text{Duty Cycle for TTL inputs HIGH}$
 $N_T = \text{Number of TTL inputs at } D_H$
 $I_{CCD} = \text{Dynamic Current caused by an input transition pair (HLH or LHL)}$
 $f_0 = \text{Clock frequency for registered devices, otherwise zero}$
 $f_1 = \text{Input signal frequency}$
 $N_1 = \text{Number of inputs changing at } f_1$
All currents are in millamps and all frequencies are in megahertz.
11. Values for these conditions are examples of the I_{CC} formula. These limits are guaranteed but not tested.

Switching Characteristics^[12] Over the Operating Range

Parameter	Description	FCT374T/FCT574T				FCT374AT/FCT574AT				Unit	Fig. No. ^[13]		
		Military		Commercial		Military		Commercial					
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.				
t _{PLH} t _{PHL}	Propagation Delay Clock to Output	2.0	11.0	2.0	10.0	2.0	7.2	2.0	6.5	ns	1, 5		
t _{PZH} t _{PZL}	Output Enable Time	1.5	14.0	1.5	12.5	1.5	7.5	1.5	6.5	ns	1, 7, 8		
t _{PHZ} t _{PLZ}	Output Disable Time	1.5	8.0	1.5	8.0	1.5	6.5	1.5	5.5	ns	1, 7, 8		
t _S	Set-Up Time HIGH or LOW D to CP	2.0		2.0		2.0		2.0		ns	4		
t _H	Hold Time HIGH or LOW D to CP	1.5		1.5		1.5		1.5		ns	4		
t _W	Clock Pulse Width ^[14] HIGH or LOW	7.0		7.0		6.0		5.0		ns	5		

Parameter	Description	FCT374CT/FCT574CT				FCT374DT/ FCT574DT		Unit	Fig. No. ^[13]		
		Military		Commercial		Commercial					
		Min.	Max.	Min.	Max.	Min.	Max.				
t _{PLH} t _{PHL}	Propagation Delay Clock to Output	2.0	6.2	2.0	5.2	2.0	4.2	ns	1, 5		
t _{PZH} t _{PZL}	Output Enable Time	1.5	6.2	1.5	5.5	1.5	4.8	ns	1, 7, 8		
t _{PHZ} t _{PLZ}	Output Disable Time	1.5	5.7	1.5	5.0	1.5	4.0	ns	1, 7, 8		
t _S	Set-Up Time, HIGH or LOW D to CP	2.0		2.0		2.0		ns	4		
t _H	Hold Time, HIGH or LOW D to CP	1.5		1.5		1.5		ns	4		
t _W	Clock Pulse Width ^[14] HIGH or LOW	6.0		5.0		3.0		ns	5		

Shaded areas contain preliminary information.

Notes:

12. Minimum limits are guaranteed but not tested on Propagation Delays.
13. See "Parameter Measurement Information" in the General Information section.
14. With one data channel toggling, t_W(L)=t_W(H)=4.0 ns and t_F-t_I=1.0 ns.

**CY54/74FCT374T****CY54/74FCT574T****Ordering Information—FCT374T**

Speed (ns)	Ordering Code	Package Name	Package Type	Operating Range
4.2	CY74FCT374DTQC	Q5	20-Lead (150-Mil) QSOP	Commercial
	CY74FCT374DTSOC	S5	20-Lead (300-Mil) Molded SOIC	
5.2	CY74FCT374CTQC	Q5	20-Lead (150-Mil) QSOP	Commercial
	CY74FCT374CTSOC	S5	20-Lead (300-Mil) Molded SOIC	
6.2	CY54FCT374CTDMB	D6	20-Lead (300-Mil) CerDIP	Military
	CY54FCT374CTLMB	L61	20-Pin Square Leadless Chip Carrier	
6.5	CY74FCT374ATPC	P5	20-Lead (300-Mil) Molded DIP	Commercial
	CY74FCT374ATQC	Q5	20-Lead (150-Mil) QSOP	
	CY74FCT374ATSOC	S5	20-Lead (300-Mil) Molded SOIC	
7.2	CY54FCT374ATLMB	L61	20-Pin Square Leadless Chip Carrier	Military
10.0	CY74FCT374TQC	Q5	20-Lead (150-Mil) QSOP	Commercial
	CY74FCT374TSOC	S5	20-Lead (300-Mil) Molded SOIC	
11.0	CY54FCT374TDMB	D6	20-Lead (300-Mil) CerDIP	Military
	CY54FCT374TLMB	L61	20-Pin Square Leadless Chip Carrier-	

Ordering Information—FCT574T

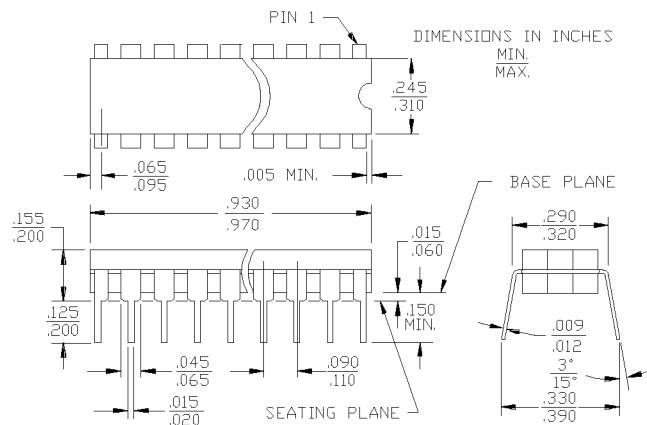
Speed (ns)	Ordering Code	Package Name	Package Type	Operating Range
4.2	CY74FCT574DTQC	Q5	20-Lead (150-Mil) QSOP	Commercial
	CY74FCT574DTSOC	S5	20-Lead (300-Mil) Molded SOIC	
5.2	CY74FCT574CTQC	Q5	20-Lead (150-Mil) QSOP	Commercial
	CY74FCT574CTSOC	S5	20-Lead (300-Mil) Molded SOIC	
6.2	CY54FCT574CTDMB	D6	20-Lead (300-Mil) CerDIP	Military
6.5	CY74FCT574ATPC	P5	20-Lead (300-Mil) Molded DIP	Commercial
	CY74FCT574ATQC	Q5	20-Lead (150-Mil) QSOP	
	CY74FCT574ATSOC	S5	20-Lead (300-Mil) Molded SOIC	
7.2	CY54FCT574ATLMB	D6	20-Lead (300-Mil) CerDIP	Military
10.0	CY74FCT574TQC	Q5	20-Lead (150-Mil) QSOP	Commercial
	CY74FCT574TSOC	S5	20-Lead (300-Mil) Molded SOIC	
11.0	CY54FCT574TDMB	D6	20-Lead (300-Mil) CerDIP	Military

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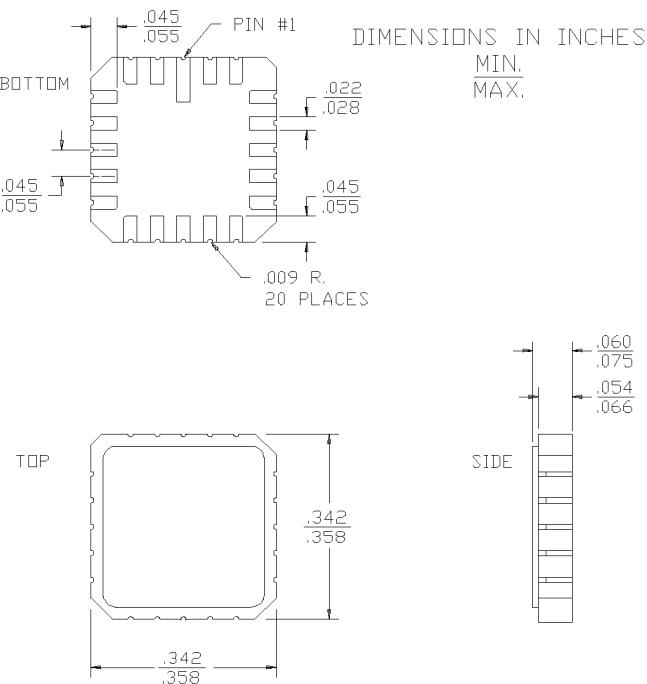
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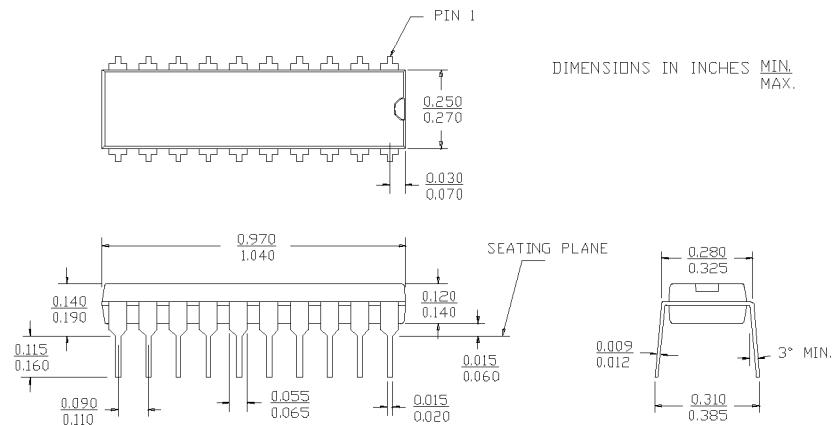
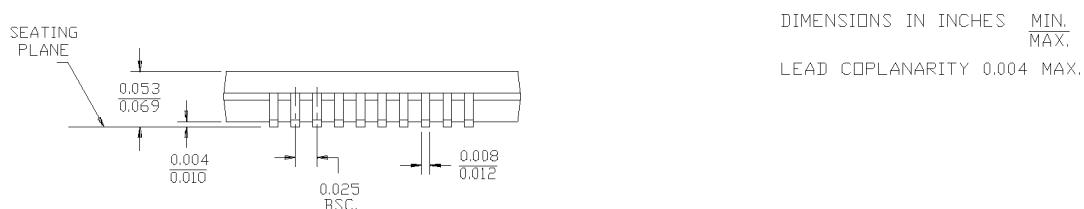
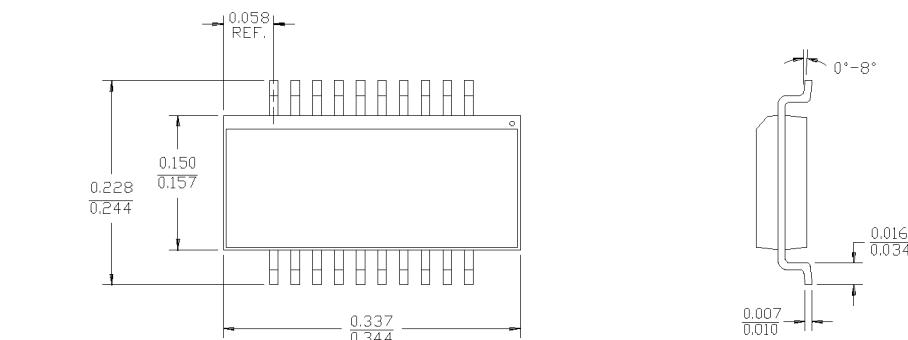
Package Diagrams

20-Lead (300-Mil) CerDIP D6
 MIL-STD-1835 D-8Config.A



20-Pin Square Leadless Chip Carrier L61
 MIL-STD-1835 C-2A



Package Diagrams (continued)
20-Lead (300-Mil) Molded DIP P5

20-Lead Quarter Size Outline Q5


Package Diagrams (continued)
20-Lead (300-Mil) Molded SOIC S5
